

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of Applicants:

Date: June 1, 2007

B. S. Beaman et al.

Group Art Unit: 2829

Serial No.: 10/145,661

Examiner: J. M. Hollington

Filed: May 14, 2002

Docket No.: YOR919990088US1

For: STRUCTURAL DESIGN AND PROCESSES TO CONTROL PROBE
POSITION ACCURACY IN A WAFER TEST PROBE ASSEMBLY

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

RESPONSE TO OFFICE ACTION DATED MARCH 1, 2007

Sir:

In response to the Office Action dated March 1, 2007, please amend the
above-identified application as follows:

Remarks begin on page 2 of this paper.